Power MOSFET

30 V, 20 A, Single N-Channel, SOIC-8 Flat Lead Package

Features

- Thermally and Electrically Enhanced Packaging Compatible with Standard SOIC-8
- New Package Provides Capability of Inspection and Probe After Board Mounting
- Ultra Low R_{DS(on)} (at 4.5 V_{GS}), Low Gate Resistance and Low Q_G
- Optimized for High Side Control Applications
- High Speed Switching Capability
- These are Pb-Free Devices

Applications

- Notebook Computer VCORE Applications
- Network Applications
- DC-DC Converters

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V _{GS}	±20	V
Continuous Drain Current	Steady	T _A = 25°C	I _D	12.3	Α
(Note 1)	State	T _A = 70°C		9.8	
	t ≤10 s	T _A = 25°C	I _D	20	
Power Dissipation (Note 1)	Steady State	T _A = 25°C	P _D	2.3	W
	t ≤10 s	T _A = 25°C	P_{D}	6.0	
Continuous Drain Current		T _A = 25°C	I _D	7.7	Α
(Note 2)	Steady	T _A = 70°C		6.2	
Power Dissipation (Note 2)	State	T _A = 25°C	P _D	0.9	W
Pulsed Drain Current	t _p =	10 μs	I _{DM}	60	Α
Operating and Storage Temperature			T _J , T _{stg}	-55 to 150	°C
Source Current (Body Diode)			I _S	6.0	Α
Single Pulse Drain-to-Source Avalanche Energy (V_{DD} = 25 V, V_{GS} = 10 V, I_{PK} = 7.5 A, L = 10 mH, R_G = 25 Ω)			E _{AS}	280	mJ
Lead Temperature for Soldering Purposes (1/8 in from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

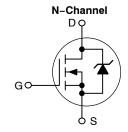
- Surface-mounted on FR4 board using 1 in sq. pad size (Cu area 1.127 in sq. [1 oz] including traces).
- Surface-mounted on FR4 board using minimum recommended pad size (Cu area 0.412 in sq.).



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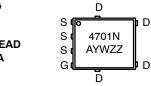
V _{(BR)DSS}	R _{DS(on)} Typ	I _D Max		
30 V	6.0 mΩ @ 10 V	20 A		
30 7	8.0 mΩ @ 4.5 V	2074		





STYLE 1

MARKING DIAGRAM & PIN ASSIGNMENT



4701N = Specific Device Code A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping [†]				
NTMFS4701NT1G	SOIC-8 FL (Pb-Free)	1500 / Tape & Reel				
NTMFS4701NT3G	SOIC-8 FL (Pb-Free)	5000 / Tape & Reel				

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE RATINGS

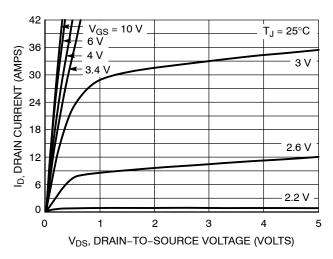
Rating	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{ heta JC}$	4.0	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{ hetaJA}$	140	
Junction-to-Ambient - t ≤ 10 s (Note 1)	$R_{ hetaJA}$	21	
Junction-to-Ambient - Steady State (Note 1)	$R_{ hetaJA}$	55	

FLECTRICAL CHARACTERISTICS (T. - 25°C unless otherwise noted)

Characteristic	Symbol	Test Condition	on	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				•	•	•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				7.2		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 \text{ V}, V_{DS} = 24 \text{ V}$ $T_{J} = 25^{\circ}\text{C}$ $T_{J} = 125^{\circ}\text{C}$				1.0	μΑ
						50	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} =$				±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 2$	250 μΑ	1.0		3.0	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 4.5 V, I _D =	= 17 A		8.0	11	mΩ
		V _{GS} = 10 V, I _D =	20 A		6.0	8.0	
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 20 A			70		S
CHARGES, CAPACITANCES AND GATE R	ESISTANCE				•	•	•
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1.0 MHz, V _{DS} = 24 V			1280		pF
Output Capacitance	C _{OSS}				500		
Reverse Transfer Capacitance	C _{RSS}				120		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V, I _D = 20 A			11	15	nC
Threshold Gate Charge	Q _{G(TH)}				1.1		
Gate-to-Source Charge	Q_{GS}				2.0		
Gate-to-Drain Charge	Q_{GD}				6.0		
Gate Resistance	R_{G}				1.4		Ω
SWITCHING CHARACTERISTICS, V _{GS} = 4.	5 V (Note 4)					•	
Turn-On Delay Time	t _{d(ON)}				9.0		ns
Rise Time	t _r	V _{GS} = 10 V, V _{DD} =	= 15 V,		4.0]
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 1.0 \text{ A}, R_G = 6.0 \Omega$			29		
Fall Time	t _f				19		
DRAIN-SOURCE DIODE CHARACTERISTI	cs					•	
Forward Diode Voltage	V_{SD}	., ., ., ., .,	T _J = 25°C		0.75	1.0	V
		$V_{GS} = 0 \text{ V}, I_{S} = 6.0 \text{ A}$	T _J = 125°C		0.55		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_S/dt = 100 \text{ A/}\mu\text{s,}$ $I_S = 6.0 \text{ A}$			34		ns
Charge Time	ta				16		
Discharge Time	t _b				18		
Reverse Recovery Charge	Q _{RR}				27		nC

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

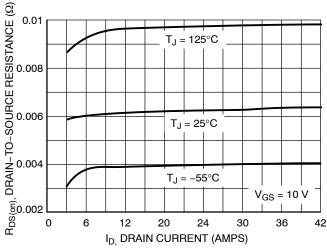
TYPICAL PERFORMANCE CURVES



 $V_{DS} \ge 10 \text{ V}$ 36 DRAIN CURRENT (AMPS) 30 24 18 $T_J = 25^{\circ}C$ 12 <u>ص</u> 6 -55°C 0 0 3 5 2 V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



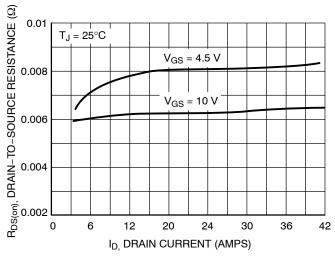
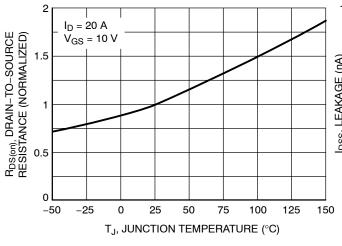


Figure 3. On-Resistance vs. Drain Current and Temperature

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



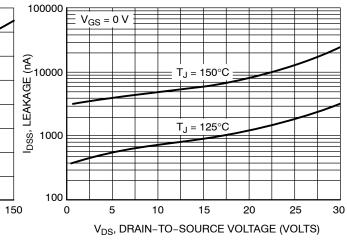
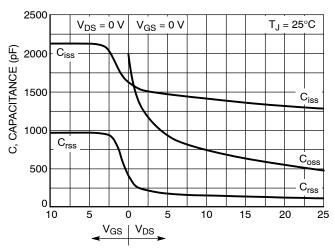


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

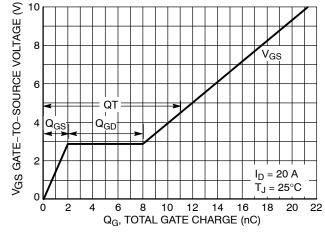


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge



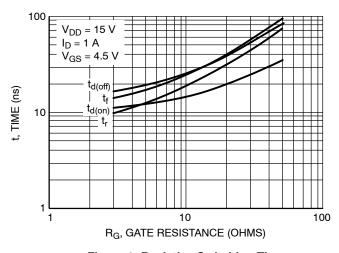


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

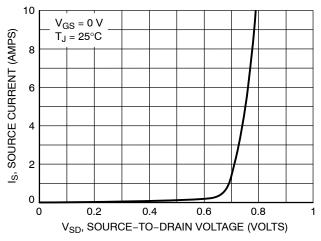


Figure 10. Diode Forward Voltage vs. Current

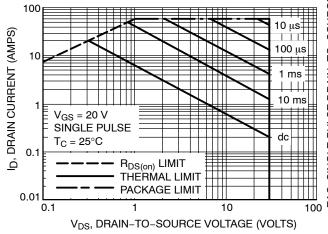


Figure 11. Maximum Rated Forward Biased Safe Operating Area

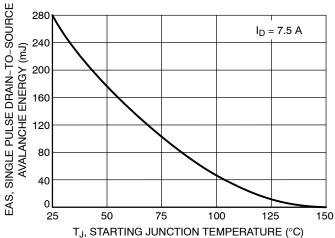
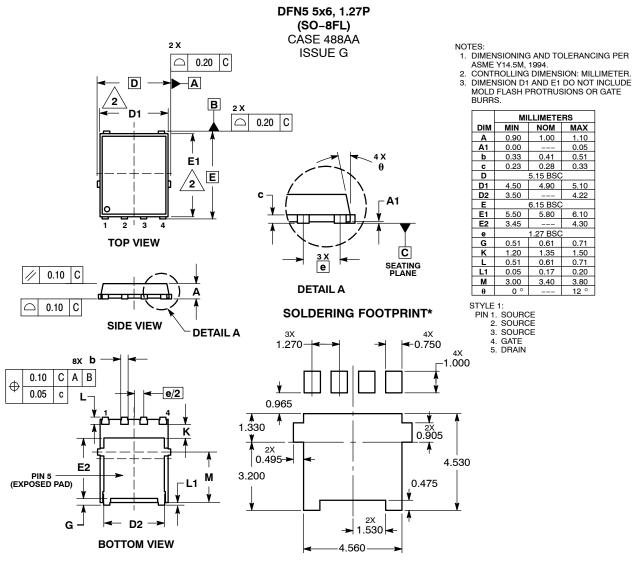


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

PACKAGE DIMENSIONS



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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